

## STL70N4LLF5

# Automotive-grade N-channel 40 V, 6.1 mΩ typ., 18 A STripFET™ F5 Power MOSFET in a PowerFLAT™ 5x6 package

Datasheet - production data

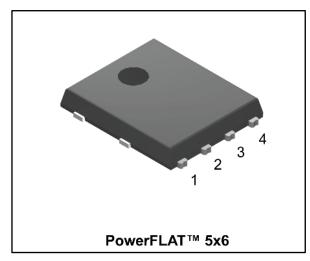
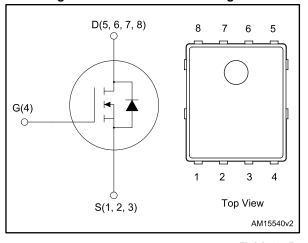


Figure 1: Internal schematic diagram



### **Features**

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	ID
STL70N4LLF5	40 V	6.7 mΩ	18 A



- AEC-Q101 qualified
- Low on-resistance R<sub>DS(on)</sub>
- High avalanche ruggedness
- Low gate drive power loss
- Wettable flank package

## **Applications**

• Switching applications

### **Description**

This N-channel Power MOSFET is developed using the STripFET<sup>™</sup> F5 technology and has been optimized to achieve very low on-state resistance, contributing to a FoM that is among the best in its class.

**Table 1: Device summary** 

Order code	Marking	Package	Packing
STL70N4LLF5	70N4LLF5	PowerFLAT™ 5x6	Tape and reel

Contents STL70N4LLF5

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STL70N4LLF5 Electrical ratings

# 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit	
V <sub>DS</sub>	Drain-source voltage	40	V	
$V_{GS}$	Gate-source voltage	± 22	V	
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>C</sub> = 25 °C	70		
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>c</sub> = 100 °C	44		
I <sub>D</sub> <sup>(2)</sup>	Drain current (continuous) at T <sub>pcb</sub> = 25 °C 18			
I <sub>D</sub> <sup>(2)</sup>	Drain current (continuous) at T <sub>pcb</sub> = 100 °C 11.5			
I <sub>DM</sub> <sup>(1)(3)</sup>	Drain current (pulsed)	72		
P <sub>TOT</sub> <sup>(1)</sup>	Total dissipation at T <sub>C</sub> = 25 °C	72	W	
P <sub>TOT</sub> <sup>(2)</sup>	Total dissipation at T <sub>pcb</sub> = 25 °C	4.8	VV	
T <sub>stg</sub>	Storage temperature range			
TJ	Operation junction temperature range	-55 to 175	°C	

#### Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit	
R <sub>thj-case</sub>	Thermal resistance junction-case 2.0		°CAM	
R <sub>thj-pcb</sub> <sup>(1)</sup>	Thermal resistance junction-pcb	31.3	°C/W	

#### Notes:

Table 4: Avalanche data

Symbol	Parameter		Unit
l <sub>AV</sub>	Not-repetitive avalanche current (pulse width limited by T <sub>jmax.</sub> )	9	Α
Eas	Single pulse avalanche energy (starting $T_J = 25$ °C, $I_D = I_{AV}$ , $V_{DD} = 24$ V)	470	mJ

 $<sup>^{(1)} \</sup>mbox{The value}$  is rated according to  $R_{\mbox{\scriptsize thj-c}}.$ 

 $<sup>\</sup>ensuremath{^{(2)}} The value is rated according to <math display="inline">R_{thj\text{-pcb.}}$ 

<sup>(3)</sup>Pulse width limited by safe operating area

 $<sup>^{(1)}</sup>$ When mounted on FR-4 board of 1 inch², 2oz Cu, t < 10 s

Electrical characteristics STL70N4LLF5

## 2 Electrical characteristics

(T<sub>C</sub> = 25 °C unless otherwise specified)

Table 5: On/off-states

Symbol	Parameter	Parameter Test conditions		Тур.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0 V	40			V
IDSS	Zero gate voltage drain current	$V_{GS} = 0 V$ $V_{DS} = 40 V$			1	
IDSS	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}$ $V_{DS} = 40 \text{ V}, T_J = 125 \text{ °C }^{(1)}$			10	μА
Igss	Gate-body leakage current	V <sub>GS</sub> = ± 22 V, V <sub>DS</sub> = 0 V			±100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	1		2.5	V
D	Static drain-source	V <sub>G</sub> S = 10 V, I <sub>D</sub> = 9 A		6.1	6.7	m0
R <sub>DS(on)</sub>	on-resistance	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 9 A		7.6	9.0	mΩ

#### Notes:

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>iss</sub>	Input capacitance		-	1570	-	pF
Coss	Output capacitance	V <sub>DS</sub> = 25 V, f = 1 MHz,	-	257	-	pF
Crss	Reverse transfer capacitance	V <sub>GS</sub> = 0 V		32	-	pF
Qg	Total gate charge	V <sub>DD</sub> = 15 V, I <sub>D</sub> = 18 A,	ı	12.9	ı	nC
Qgs	Gate-source charge	V <sub>G</sub> S = 4.5 V	ı	3.9	ı	nC
$Q_{gd}$	Gate-drain charge	(see Figure 14: "Test circuit for gate charge behavior")	1	5.3	1	nC
R <sub>G</sub>	Gate input resistance	f = 1 MHz, gate DC bias = 0 V, test signal level = 20 mV, I <sub>D</sub> = 0 A	-	1.5	-	Ω

**Table 7: Switching times** 

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time	V <sub>DD</sub> = 15 V, I <sub>D</sub> = 9 A,	1	14	ı	ns
tr	Rise time	$R_G = 4.7 \Omega$ , $V_{GS} = 10 V$	-	42	-	ns
t <sub>d(off)</sub>	Turn-off delay time	(see Figure 13: "Test circuit for	-	37	-	ns
t <sub>f</sub>	Fall time	resistive load switching times"	-	5.2	-	ns

<sup>&</sup>lt;sup>(1)</sup>Defined by design, not subject to production test

Table 8: Source-drain diode

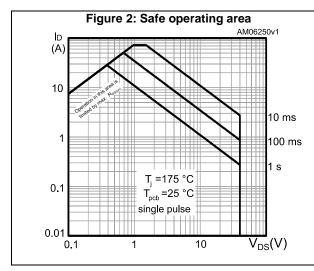
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		-		18	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current pulsed		-		72	Α
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 18 A, V <sub>GS</sub> = 0 V			1.1	٧
t <sub>rr</sub>	Reverse recovery time		-	27.2		ns
Qrr	Reverse recovery charge $I_{SD} = 18 \text{ A}, \text{ di/dt} = 100 \text{ A/µs}, V_{DD} = 25 \text{ V}, T_J = 150 ^{\circ}\text{C}$		-	24.5		nC
I <sub>RRM</sub>	Reverse recovery current	7 VDD - 20 V, 15 - 100 O	-	1.8		Α

#### Notes:

 $<sup>\</sup>ensuremath{^{(1)}}\mbox{Pulse}$  width limited by safe operating area.

 $<sup>^{(2)}\</sup>text{Pulsed:}$  pulse duration = 300  $\mu\text{s},$  duty cycle 1.5%

## 2.2 Electrical characteristics (curves)



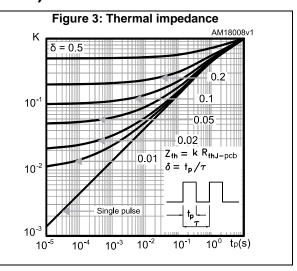


Figure 4: Output characteristics

ID

AM06251v1

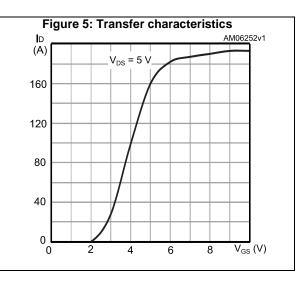
160

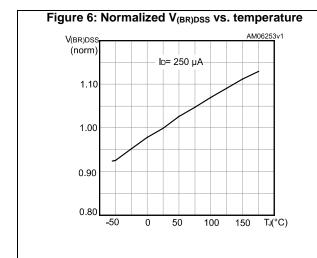
120

4 V

80

0 2 4 6 8 V<sub>DS</sub>(V)





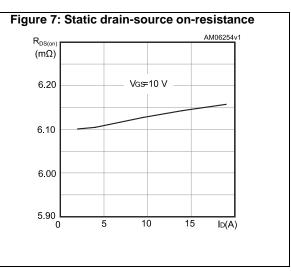


Figure 8: Gate charge vs. gate-source voltage

VGS
(V)
12
| VDD=15 V |
|D=18 A |
10
8
6
4
2
0
0 5 10 15 20 25 Qg(nC)

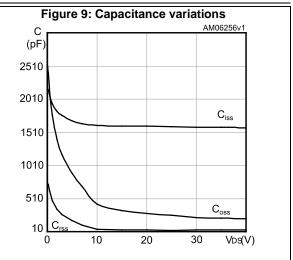
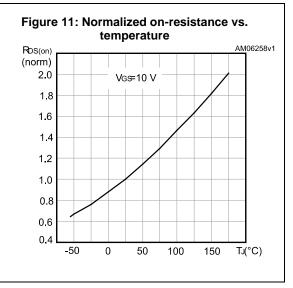
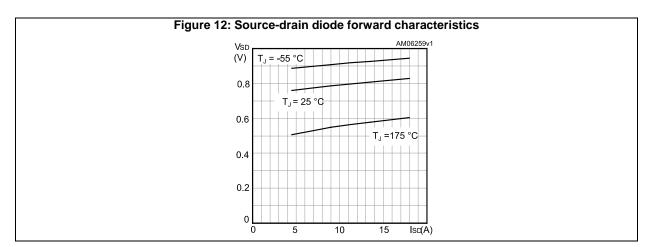


Figure 10: Normalized gate threshold voltage vs. temperature  $V_{GS(th)}$ (norm) Vos=Vgs 1.2 lo= 250 μA 1.0 0.8 0.6 0.4 -50 0 50 100 150 TJ(°C)





Test circuits STL70N4LLF5

## 3 Test circuits

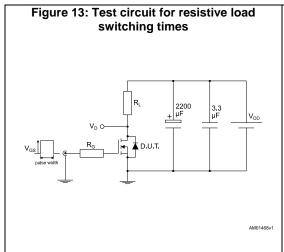
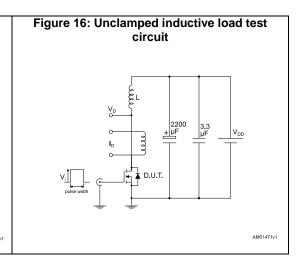
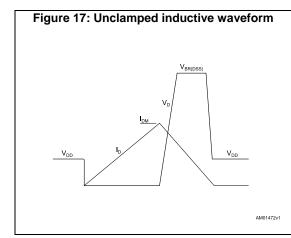


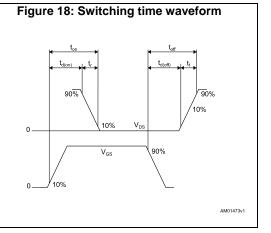
Figure 14: Test circuit for gate charge behavior

12 V 47 KQ 100 NF 1 KQ 100 N

Figure 15: Test circuit for inductive load switching and diode recovery times







5/

## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

# 4.1 PowerFLAT™ 5x6 single island WF type C package information

Figure 19: PowerFLAT™ 5x6 WF type C package outline

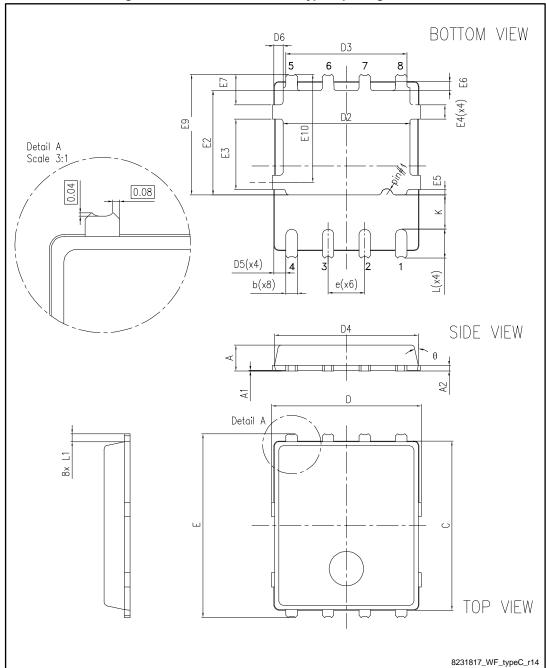
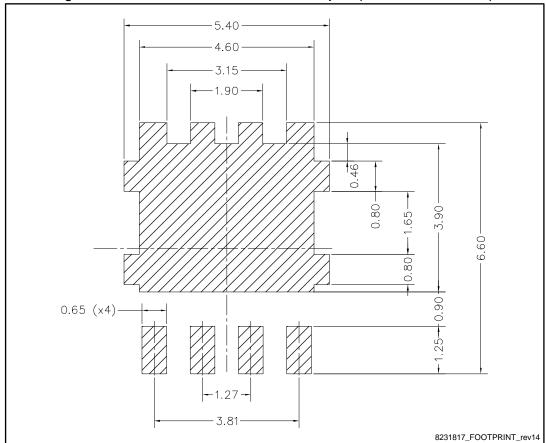


Table 9: PowerFLAT™ 5x6 WF type C mechanical data

Di		mm	
Dim.	Min.	Тур.	Max.
А	0.80		1.00
A1	0.02		0.05
A2		0.25	
b	0.30		0.50
С	5.80	6.00	6.10
D	5.00	5.20	5.40
D2	4.15		4.45
D3	4.05	4.20	4.35
D4	4.80	5.00	5.10
D5	0.25	0.40	0.55
D6	0.15	0.30	0.45
е		1.27	
Е	6.20	6.40	6.60
E2	3.50		3.70
E3	2.35		2.55
E4	0.40		0.60
E5	0.08		0.28
E6	0.20	0.325	0.45
E7	0.85	1.00	1.15
E9	4.00	4.20	4.40
E10	3.55	3.70	3.85
K	1.05		1.35
L	0.90	1.00	1.10
L1	0.175	0.275	0.375
θ	0°		12°





STL70N4LLF5 Package information

## 4.2 Packing information

Figure 21: PowerFLAT™ 5x6 WF tape (dimensions are in mm)

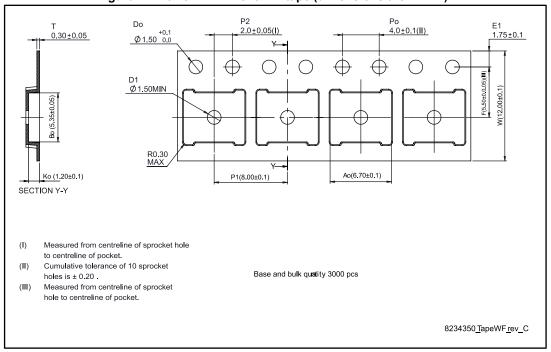
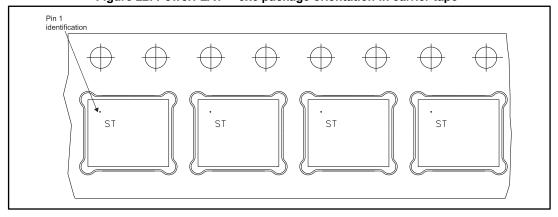


Figure 22: PowerFLAT™ 5x6 package orientation in carrier tape



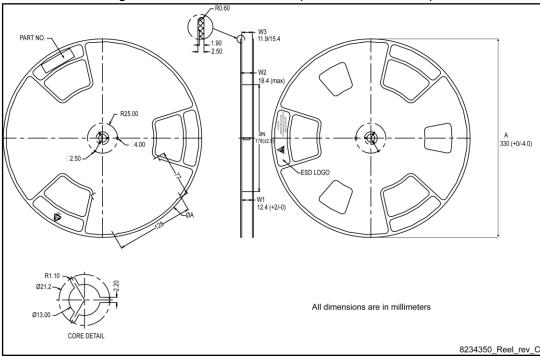


Figure 23: PowerFLAT™ 5x6 reel (dimensions are in mm)

STL70N4LLF5 Revision history

# 5 Revision history

Table 10: Document revision history

Date	Revision	Changes
01-Dec-2008	1	First release.
18-Jul-2011	2	Section 4: Package mechanical data has been modified:  - Added Table 9: PowerFLAT™ 5x6 type S-C mechanical data  - Added Figure 19: PowerFLAT™ 5x6 type S-C mechanical data  - Added PowerFLAT™ 5x6 type C-B mechanical data  - Added PowerFLAT™ 5x6 type C-B drawing Minor text changes.
21-Dec-2011	3	Section 4: Package mechanical data has been modified.
25-Jan-2013	4	<ul> <li>Table 1: Device summary has been updated.</li> <li>-Minor text changes.</li> <li>-Changed: Figure 1</li> <li>-Added Section 5: Packaging mechanical data.</li> </ul>
12-Feb-2013	5	-Updated T <sub>J</sub> and T <sub>stg</sub> in Table 2: Absolute maximum ratings.  — Updated Section 4: Package mechanical data and Figure 22:  PowerFLAT™ 5x6 package orientation in carrier tape.
24-May-2013	6	- Modified: title and Section 4: Package mechanical data - Minor text changes.
17-Dec-2014	7	<ul> <li>Modified: Figure 2 and 3</li> <li>Updated: Figure 13, 14, 15 and 16</li> <li>Updated: Section 4: Package mechanical data and Section 5: Packaging mechanical data</li> <li>Minor text changes.</li> </ul>
08-Apr-2016	8	<ul> <li>Updated Section 4: Package information and Section 4.1: Packing information</li> <li>Minor text changes.</li> </ul>
22-Sep-2016	9	Updated V <sub>GS(th)</sub> in <i>Table 5: "On/off-states"</i> .

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